

**BASTION : board and SoC test instrumentation for ageing and no failure found**

**Jutman, Artur**; Lotz, Christophe; Larsson, Erik; Sonza Reorda, Matteo; **Jenihhin, Maksim**; **Raik, Jaan** Proceedings of the 2017 Design, Automation & Test in Europe (DATE) : 27-31 March 2017, Swisstech, Lausanne, Switzerland 2017 / p. 115-120 : ill <https://doi.org/10.23919/DATE.2017.7926968>

**Embedded instrumentation toolbox for screening marginal defects and outliers for production**

**Odintsov, Sergei**; Jutman, Artur; Devadze, Sergei; **Aleksejev, Igor** IEEE AUTOTESTCON 2017 : Schaumburg, USA, Sept 11-14, 2017 : proceedings 2017 / p. 336-334 : ill <https://doi.org/10.1109/AUTEST.2017.8080516>

**Health management for self-aware SoCs based on IEEE 1687 infrastructure**

**Shibin, Konstantin**; **Devadze, Sergei**; Jutman, Artur; Grabmann, Martin; Pricken, Robin IEEE Design & Test 2017 / p. 27-35 : ill <https://doi.org/10.1109/MDAT.2017.2750902> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

**Holistic IJTAG-based external and internal fault monitoring in UAVs**

**Ahmed, Faisal**; **Jenihhin, Maksim** arXiv.org 2023 / 6 p. : ill <https://doi.org/10.48550/arXiv.2303.01816>